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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/573,160	03/23/2006	Shunpei Yamazaki	740756-2936	6623
22204 NIXON PEAB	7590 10/25/2007 ODY, LLP	EXAMINER		
401 9TH STRE SUITE 900		LEE, CALVIN		
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	,		2818	
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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

- .		Application No.	Applicant(s)
		10/573,160	YAMAZAKI, SHUNPEI
	Office Action Summary	Examiner	Art Unit
	·	Calvin Lee	2818
Period fo	The MAILING DATE of this communication app or Reply	ears on the cover sheet with the c	orrespondence address
A SHOWHIC - Exter after - If NO - Failu Any r	ORTENED STATUTORY PERIOD FOR REPLY CHEVER IS LONGER, FROM THE MAILING DATE is not soft time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. In period for reply is specified above, the maximum statutory period were to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing and patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be timulated and will expire SIX (6) MONTHS from cause the application to become ABANDONE	N. hely filed the mailing date of this communication. D (35 U.S.C. § 133).
Status			
2a)□	Responsive to communication(s) filed on This action is FINAL . 2b) This Since this application is in condition for allowar closed in accordance with the practice under E	action is non-final. nce except for formal matters, pro	
Dispositi	on of Claims	·	
5)	Claim(s) 1-100 is/are pending in the application 4a) Of the above claim(s) is/are withdraw Claim(s) is/are allowed. Claim(s) 1-100 is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and/or on Papers The specification is objected to by the Examiner The drawing(s) filed on 23 March 2006 is/are: a Applicant may not request that any objection to the or Replacement drawing sheet(s) including the correction The oath or declaration is objected to by the Examiner The oath or declaration is objected to by the Examiner Replacement drawing sheet(s) including the correction to the or declaration is objected to by the Examiner The oath of the	r election requirement. r. a)⊠ accepted or b)□ objected to drawing(s) be held in abeyance. See ion is required if the drawing(s) is objected to the drawing(s) is objected.	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).
Priority u	ınder 35 U.S.C. § 119		
a)[Acknowledgment is made of a claim for foreign All b) Some * c) None of: 1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the prior application from the International Bureau see the attached detailed Office action for a list of	s have been received. s have been received in Application ity documents have been receive I (PCT Rule 17.2(a)).	on No ed in this National Stage
2) Notice 3) Inform	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO/SB/08) r No(s)/Mail Date 3/23/06, 6/30/06 & 2/8/07.	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal Pa 6) Other:	te

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OFFICE ACTION

Claim Rejections - 35 U.S.C. § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious to one having skills in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention made.
- 2. Claims 1-100 are rejected under 35 U.S.C. 103(a) as being unpatentable over *Kurimoto* (US 5,405,787) or *Kudo* (US 6,420261), in view of *APA* (Applicant's Prior Art).

Kurimoto discloses a method for manufacturing a semiconductor device, comprising of:

- -forming a first insulating film by discharging a composition including an insulator;
- -forming a second insulating film 10 over the first insulating film 2 [Fig. 14(a)];
- -forming a mask pattern 11 on the second insulating film [Fig. 14(b)]; and
- -forming an opening by etching the first insulating film 2 by using the second insulating film 10 as a mask [Fig. 14(c) and col. 15, ln.7]

Kudo discloses a method for manufacturing a semiconductor device, comprising of:

- -forming a first insulating film by discharging a composition including an insulator;
- -forming a second insulating film 32 over the first insulating film 31 [Fig. 3F];
- -forming a mask pattern 33 on the second insulating film [Fig. 3J]; and
- -forming an opening by etching the first insulating film 31 by using the second insulating film 32 as a mask [Fig. 3K and col. 7, ln.47].

Neither *Kurimoto* nor *Kudo* suggests forming a mask pattern by performing light-exposure.

APA discloses forming a mask pattern by performing light-exposure and development.

It would have been obvious to one having skills in the art to utilize the teaching of *APA*, and thus arrive at the claimed invention. The motivation to do so would have been to form a small-size mask been etched using a well-known light-exposure technique.

3. Claims 1-100 are rejected under 35 U.S.C. 103(a) as being unpatentable over *APA* (Applicant's Prior Art) in view of *Kikuchi et al* (JP 61-171.151), *Hirabayashi* (JP 04-196.133) or *Iwabuchi et al* (JP 2006-040.940).

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APA discloses a method for manufacturing a semiconductor device, comprising at least the step of forming a resist (by performing light-exposure and development) on/over an insulating film, which has been formed by spin coating a composition. APA further discloses forming an opening by selectively etching the insulating film by using the resist as a mask, not by etching "a first insulating film by using a second insulating film as a mask." Nevertheless, such multi-layer etching is known in the semiconductor processing art as evidenced by Kikuchi et al disclosing to form an opening 10 by etching a first insulating film 4 by using a second insulating film 5 as a mask [Figs. 1(c) & 2(a)]; Hirabayashi disclosing to form an opening by etching a first insulating film 2 by using a second insulating film 21 as a mask [Figs. 1E & 1F]; Iwabuchi et al disclosing to form an opening 14a by etching a first insulating film 14 by using a second insulating film 15 as a mask [Figs. 1(a) & 1(b)].

It would have been obvious to one having skills in the art to utilize the teaching of *Kikuchi* et al, *Hirabayashi* or *Iwabuchi* et al, and thus arrive at the claimed invention. The motivation to do so would have been to form ohmic contacts thru multi-dielector device.

Contact Information

4. Any inquiry concerning this communication from the Examiner should be directed to *Calvin Lee* at (571) 272-1896 on Mondays thru Thursdays 6:30-4:30PM. If attempts to reach the examiner by telephone are unsuccessful, Art Unit 2818's Supervisory Patent Examiner *Steven Loke* can be reached at (571) 272-1657. The fax phone number for the organization (where this application is assigned to) is (571) 273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAG or Public PAIR. For more information about the PAIR system, see http://pair-direct.uspto.gov Should you have questions on access to the PAG system, contact the Electronic Business Center (EBC) at 1-866-217-9197.

Dated: October 10, 2007

Calvin Lee

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